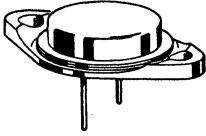


2N3021 thru 2N3026 (SILICON)

CASE 1
(TO-3)



PNP silicon power transistors for Class C power amplifiers, high-current core switching and high-speed switching and amplifier applications.

MAXIMUM RATINGS

Rating	Symbol	2N3021 2N3024	2N3022 2N3025	2N3023 2N3026	Unit
Collector-Base Voltage	V_{CB}	30	45	60	Volts
Collector-Emitter Voltage	V_{CEO}	30	45	60	Volts
Emitter-Base Voltage	V_{EB}	4.0			Volts
Collector Current	I_C	3.0			Amp
Base Current	I_B	0.5			Amp
Power Dissipation	P_D	25			Watts
Junction Operating Temperature Range	T_J	-65 to +175			°C

2N3021 thru 2N3026 (continued)

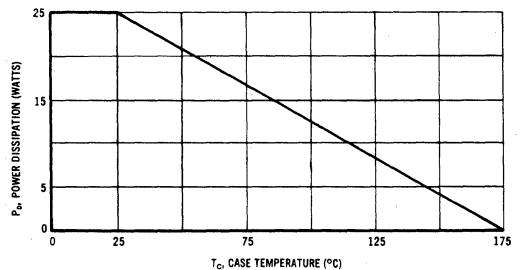
ELECTRICAL CHARACTERISTICS (At 25°C unless otherwise specified)

Characteristics	Symbol	Min	Max	Unit
Emitter-Base Cutoff Current ($V_{BE} = 4 \text{ Vdc}$)	I_{EBO}	—	1.0	mA _{dc}
Collector-Emitter Cutoff Current ($V_{CE} = 25 \text{ Vdc}, V_{BE} = 2 \text{ Vdc}$) ($V_{CE} = 40 \text{ Vdc}, V_{BE} = 2 \text{ Vdc}$) ($V_{CE} = 54 \text{ Vdc}, V_{BE} = 2 \text{ Vdc}$) ($V_{CE} = 15 \text{ Vdc}, V_{BE} = 2 \text{ Vdc}, T_C = 150^\circ\text{C}$) ($V_{CE} = 25 \text{ Vdc}, V_{BE} = 2 \text{ Vdc}, T_C = 150^\circ\text{C}$) ($V_{CE} = 35 \text{ Vdc}, V_{BE} = 2 \text{ Vdc}, T_C = 150^\circ\text{C}$)	I_{CEX}	— — — — — —	0.2 0.2 0.2 2.0 2.0 2.0	mA _{dc}
Collector-Emitter Breakdown Voltage* ($I_C = 100 \text{ mA}, I_B = 0$) ($I_C = 50 \text{ mA}, I_B = 0$) ($I_C = 20 \text{ mA}, I_B = 0$)	BV_{CEO}^*	30 45 60	— — —	V _{dc}
DC Current Gain ($I_C = 1.0 \text{ Adc}, V_{CE} = 2 \text{ Vdc}$)	h_{FE}	20 50	60 180	—
Collector-Emitter Saturation Voltage ($I_C = 3 \text{ Adc}, I_B = 0.3 \text{ Adc}$)	$V_{CE(sat)}$	— —	1.5 1.0	V _{dc}
Base-Emitter Saturation Voltage ($I_C = 3 \text{ Adc}, I_B = 0.3 \text{ Adc}$)	$V_{BE(sat)}$	—	1.5	V _{dc}
Small Signal Current Gain ($I_C = 0.5 \text{ Adc}, V_{CE} = 15 \text{ Vdc}, f = 30 \text{ MHz}$)	h_{fe}	2.0	—	—
Switching Times ($I_C = 1 \text{ Adc}, I_{B1} = I_{B2} = 100 \text{ mA}$)	$t_d + t_r$ t_s t_f	— — —	100 325 75	ns

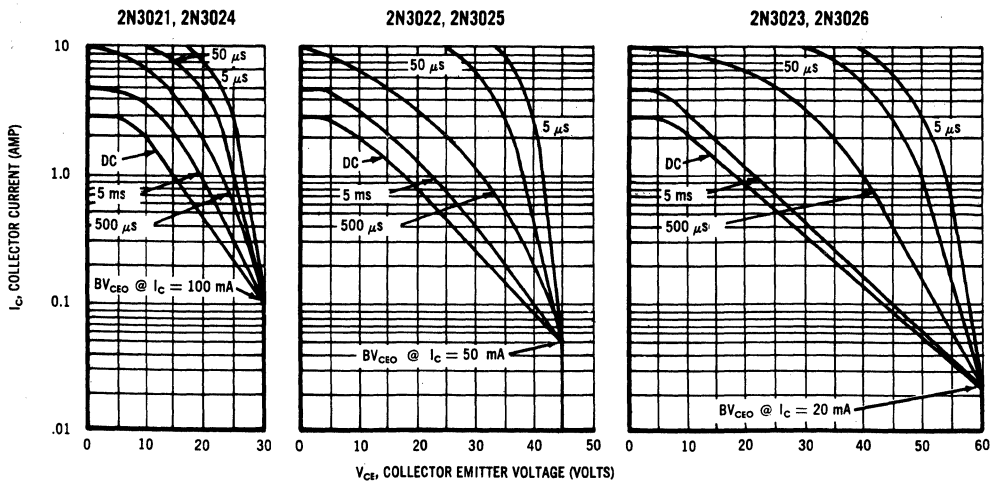
*Perform tests using sweep method to prevent heating.

POWER-TEMPERATURE DERATING CURVE

THESE TRANSISTORS ARE ALSO SUBJECT TO SAFE AREA CURVES AS INDICATED BOTH LIMITS ARE APPLICABLE AND MUST BE OBSERVED



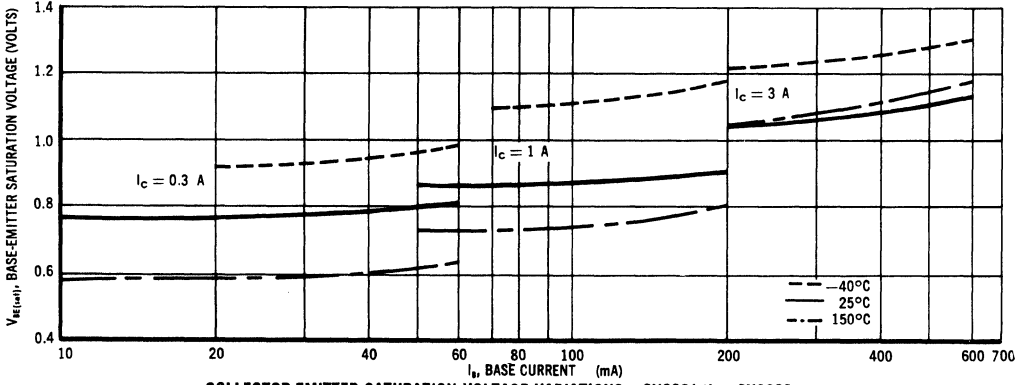
SAFE OPERATING AREAS



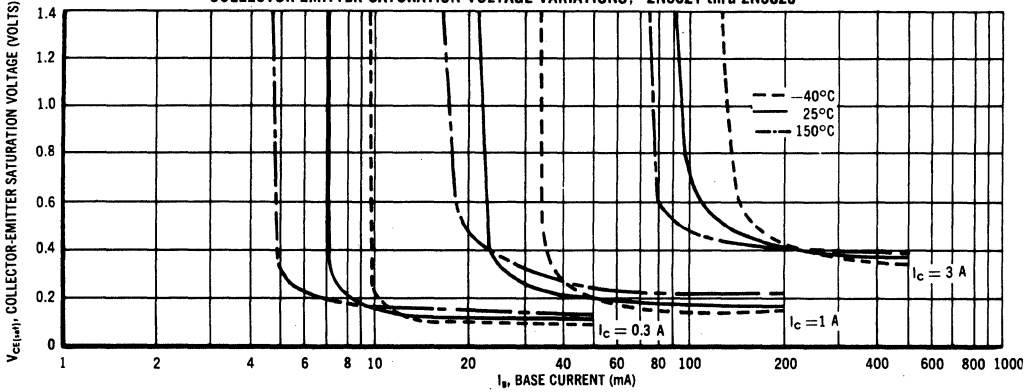
The Safe Operating Area Curves indicate I_C - V_{CE} limits below which the devices will not go into secondary breakdown. As the safe operating areas shown are independent of temperature and duty cycle, these curves can be used as long as the average power derating curve is also taken into consideration to insure operation below the maximum junction temperature.

2N3021 thru 2N3026 (continued)

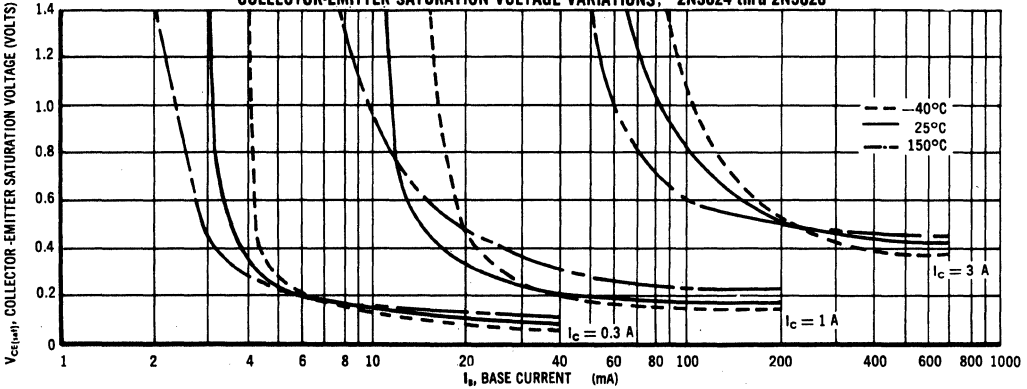
BASE-EMITTER SATURATION VOLTAGE VARIATIONS



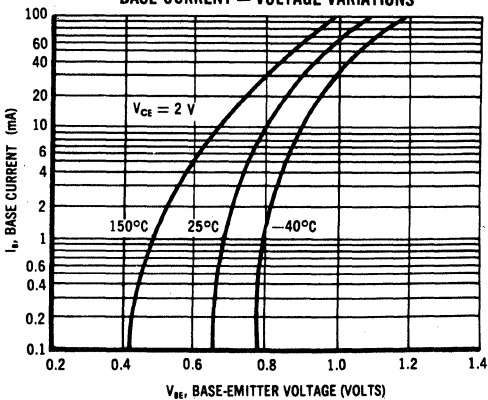
COLLECTOR-EMITTER SATURATION VOLTAGE VARIATIONS, 2N3021 thru 2N3023



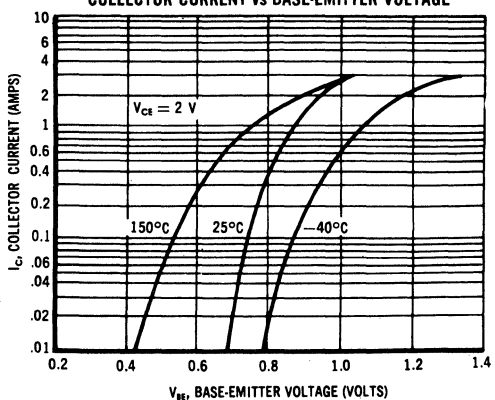
COLLECTOR-EMITTER SATURATION VOLTAGE VARIATIONS, 2N3024 thru 2N3026



BASE CURRENT - VOLTAGE VARIATIONS

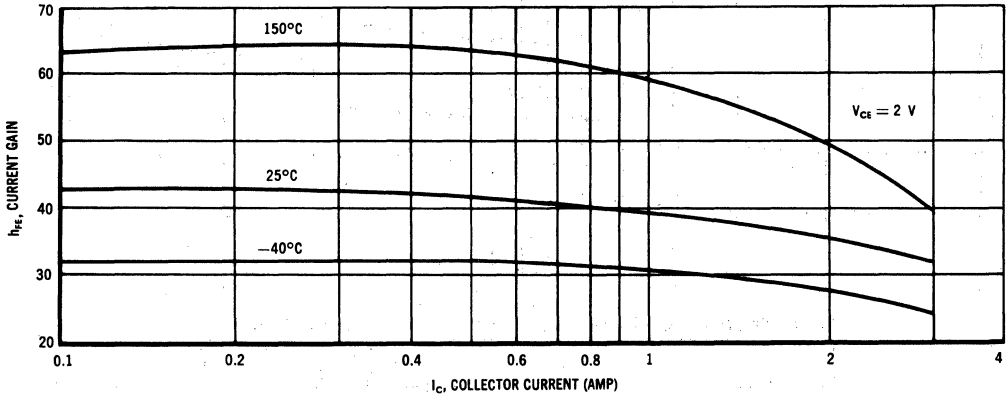


COLLECTOR CURRENT vs BASE-EMITTER VOLTAGE

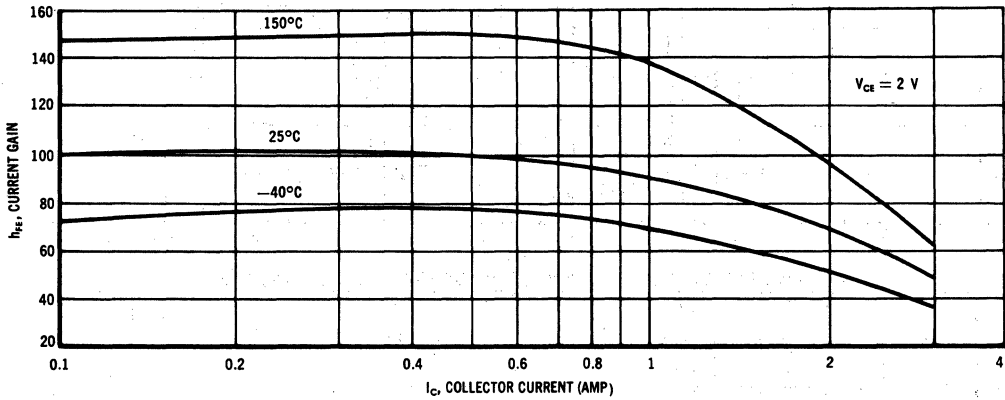


2N3021 thru 2N3026 (continued)

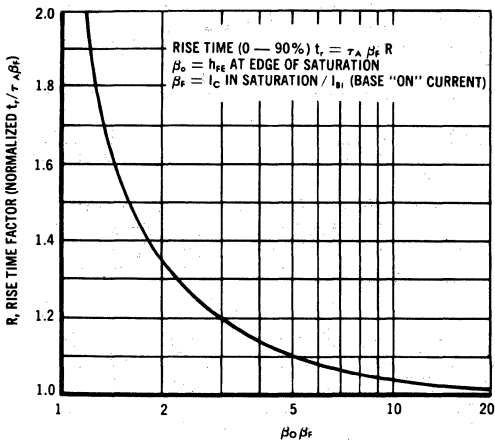
CURRENT GAIN VARIATIONS, 2N3021 thru 2N3023



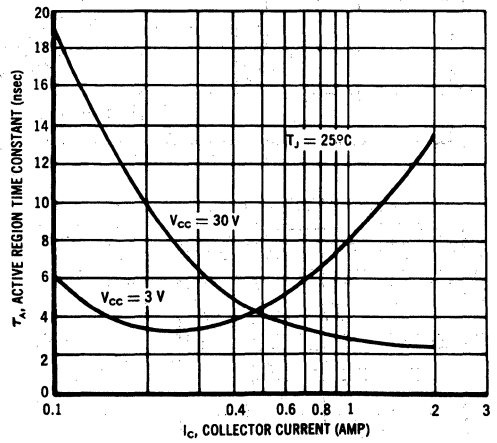
CURRENT GAIN VARIATIONS, 2N3024 thru 2N3026



RISE TIME FACTOR



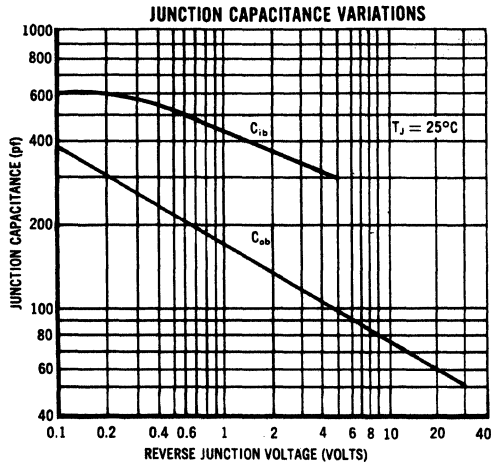
ACTIVE REGION TIME CONSTANT



SWITCHING TIME EQUATIONS

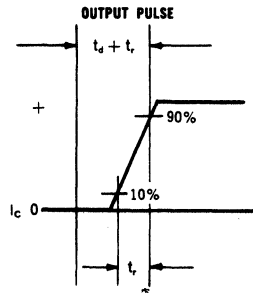
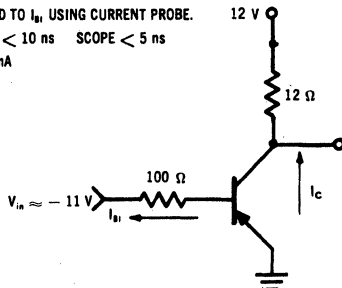
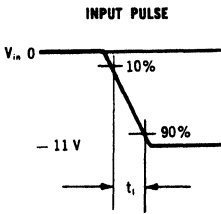
Using charge control theory and data given with this transistor, switching times for a wide variety of conditions can be readily computed.

2N3021 thru 2N3026 (continued)



TURN-ON TIME TEST CONDITIONS

V_{in} ADJUSTED TO I_{B1} USING CURRENT PROBE.
 t_1 OF INPUT < 10 ns SCOPE < 5 ns
 $I_{B1} = 100$ mA



TURN-OFF TIME TEST CONDITIONS

V_{in} ADJUSTED TO I_{B2} USING CURRENT PROBE. $T_2 < 10$ ns
 PULSE WIDTH > 10 μ s
 $I_{B2} = 100$ mA

